LFHCal SiPM QC

Yale Update

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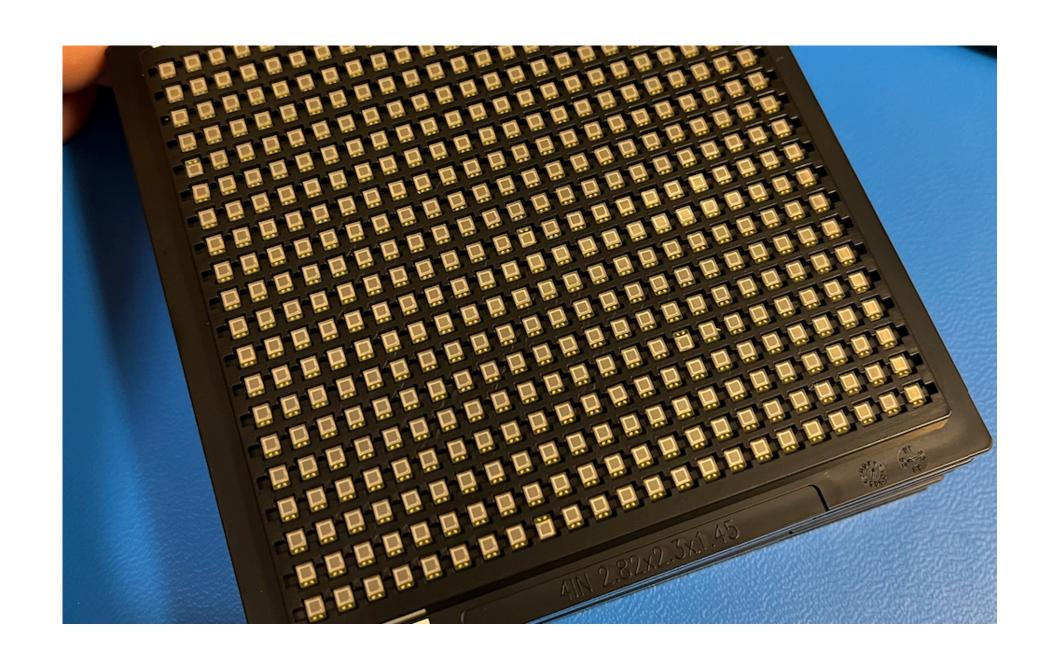
Undergrads Elisa Kim, Langan Zhu



Comparison SiPMs Received!

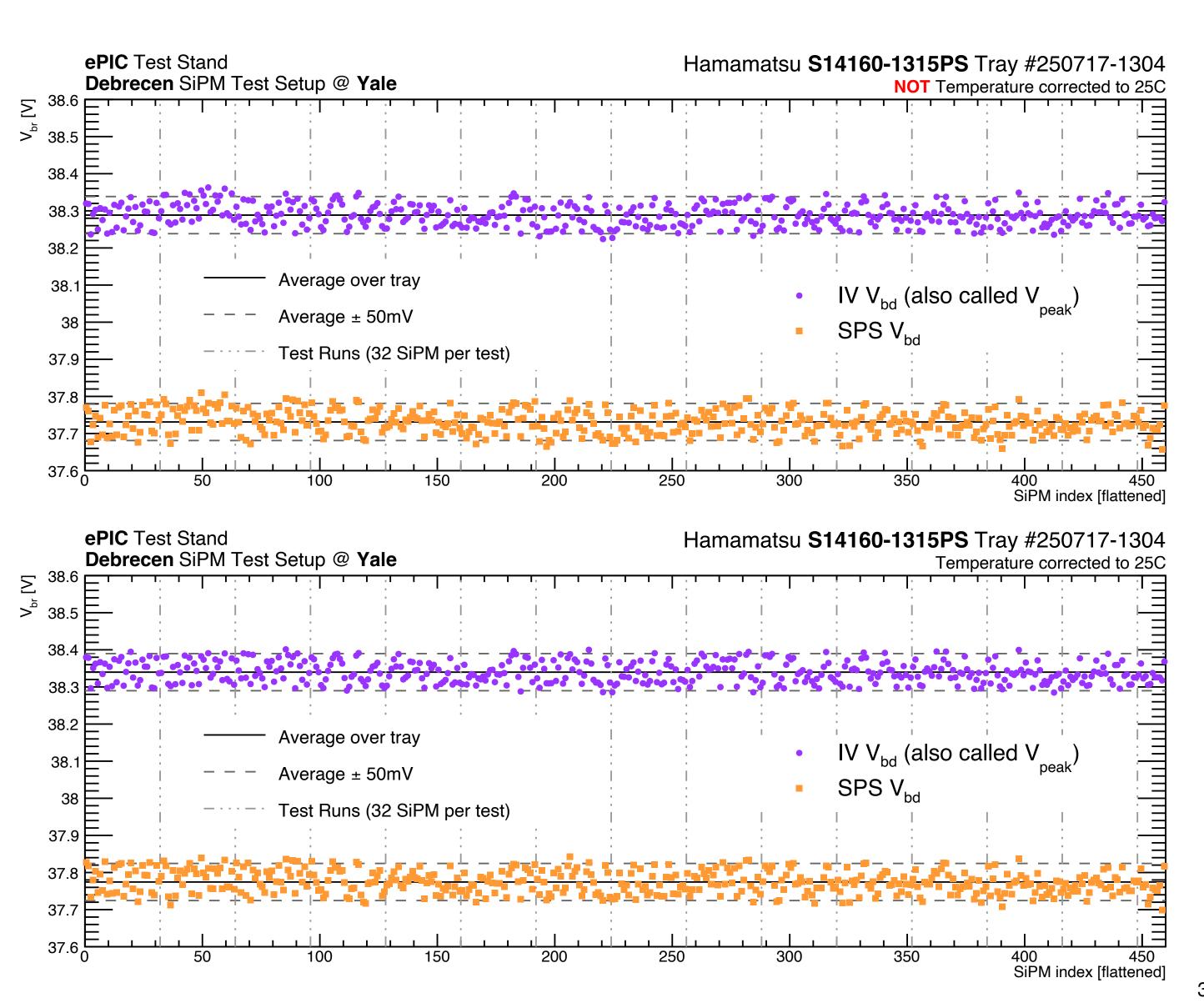
No apparent damage from shipping, or SiPMs dislodged/disordered

Maintaining order is key for correlating measurements with ORNL!

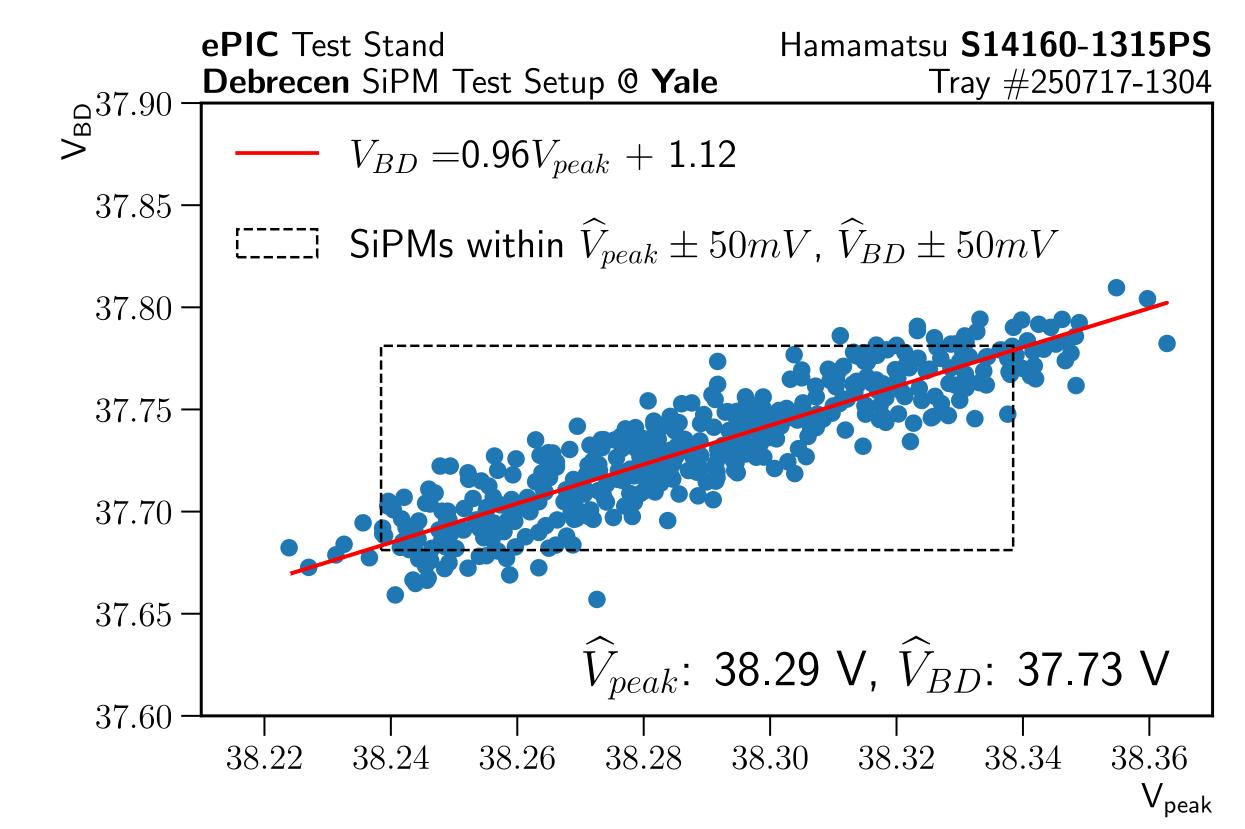




Large difference in outliers from temperature correction!

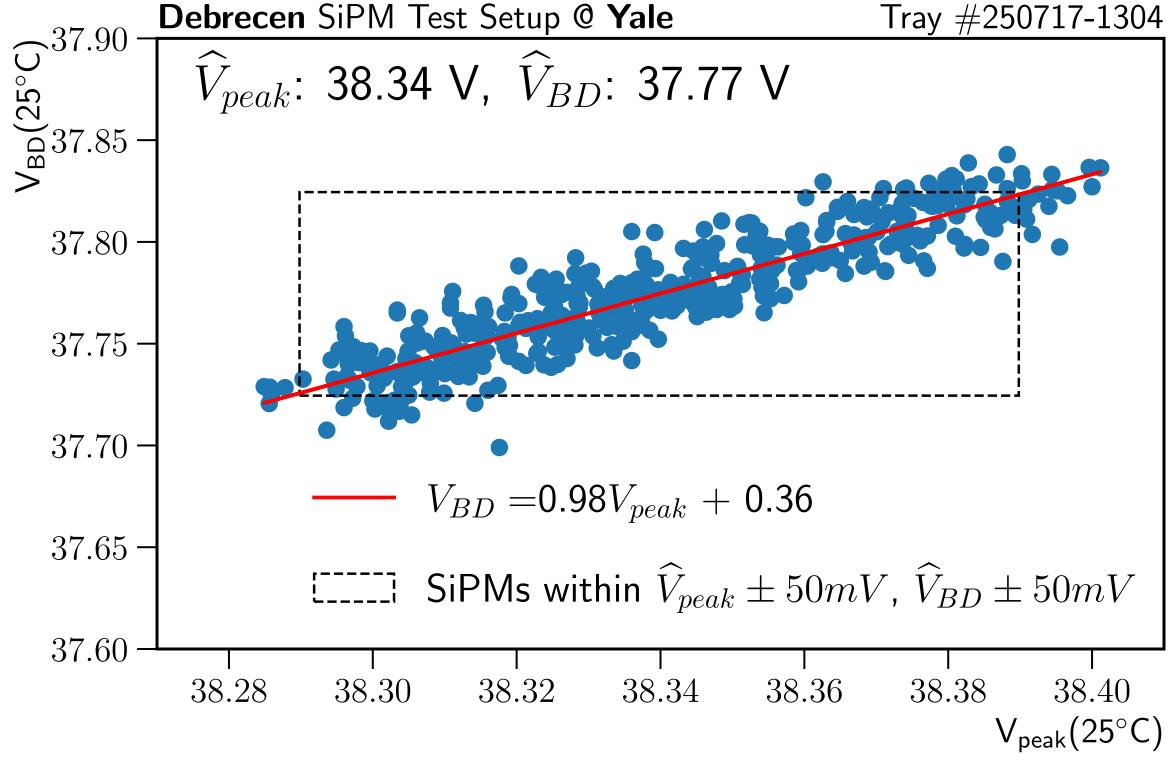


Large difference in outliers from temperature correction! (I would argue the difference is pretty small -Emily)



Using the 100mV window centered around the mean, the "outlier" SiPMs fall outside that window

V_{peak} outliers (IV): 29 (6.3%) V_{BD} outliers (SPS): 48 (10.4%)



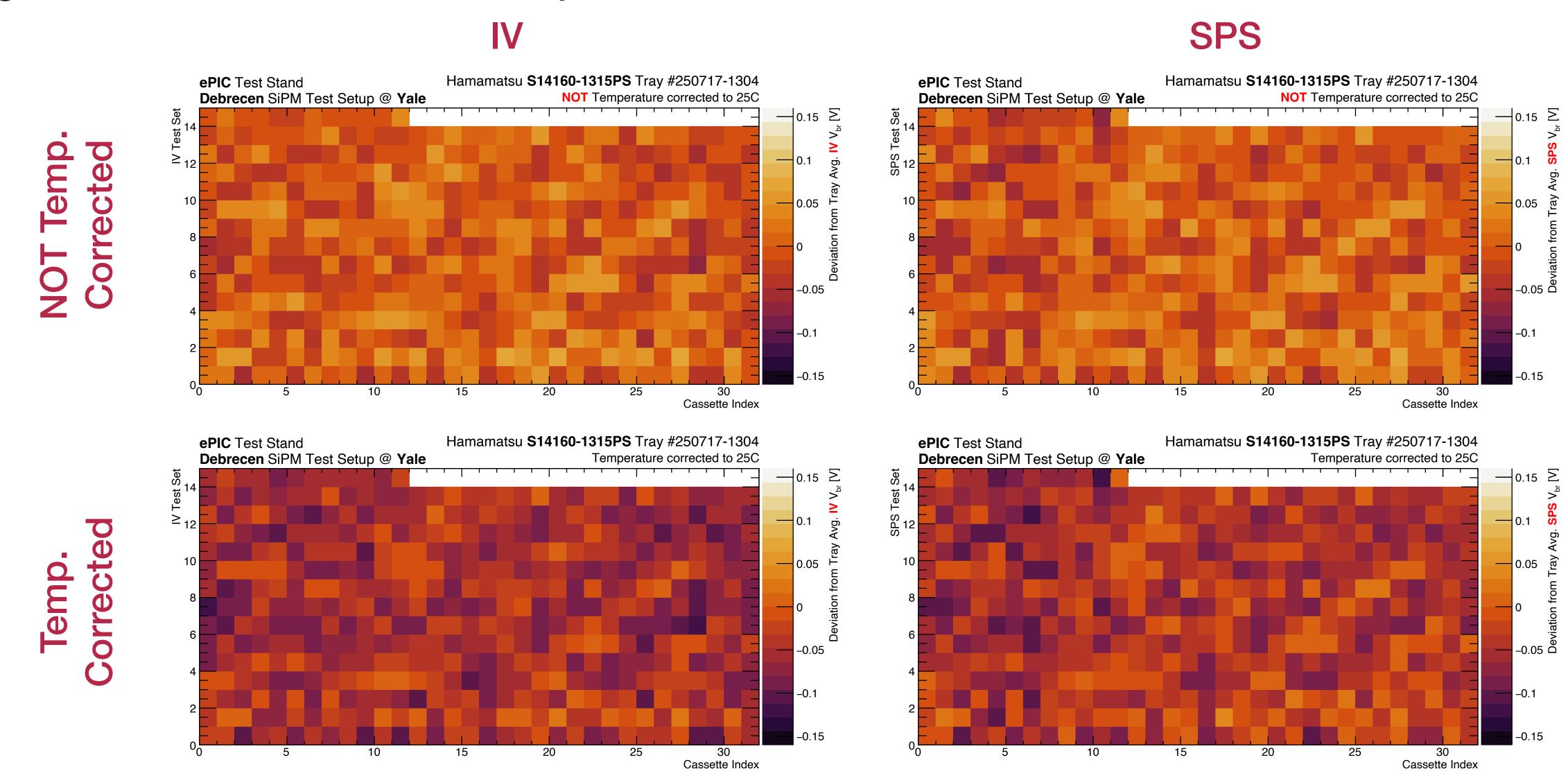
Using the 100mV window centered around the mean, the "outlier" SiPMs fall outside that window V_{peak} outliers (IV): 22 (4.8%)

V_{BD} outliers (SPS): 44 (9.6%)

ePIC Test Stand

Hamamatsu **S14160-1315PS**

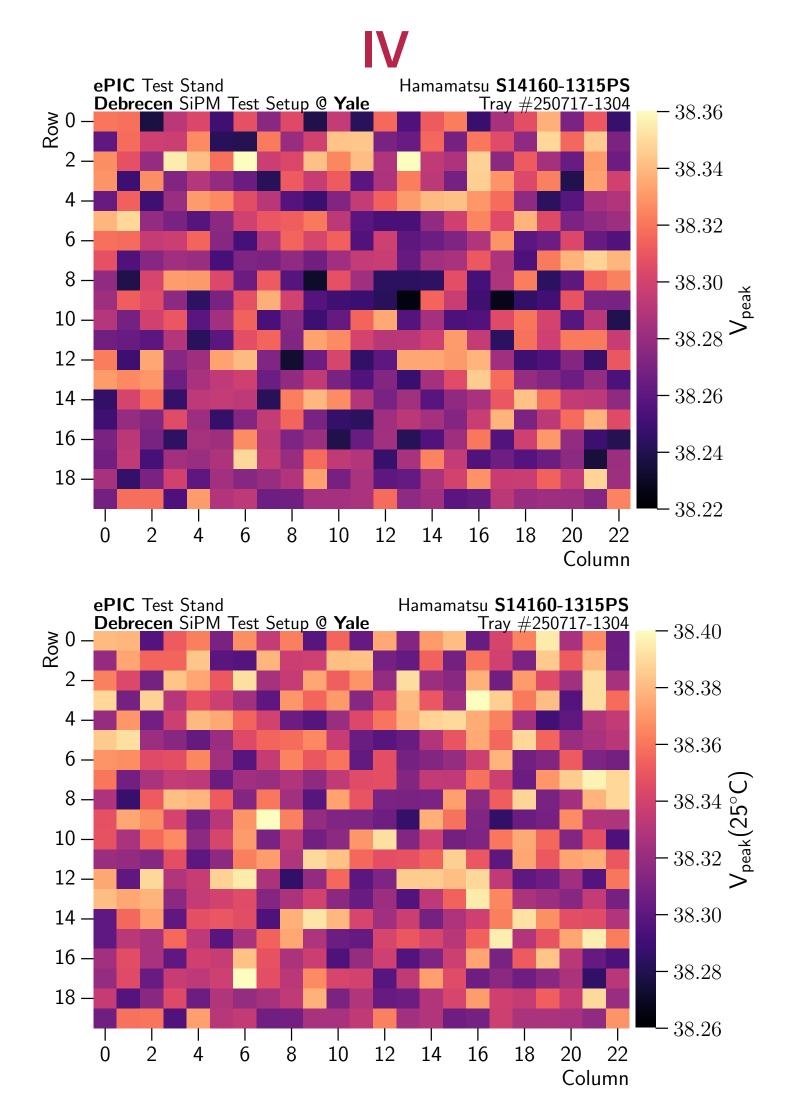
Large difference in outliers from temperature correction!

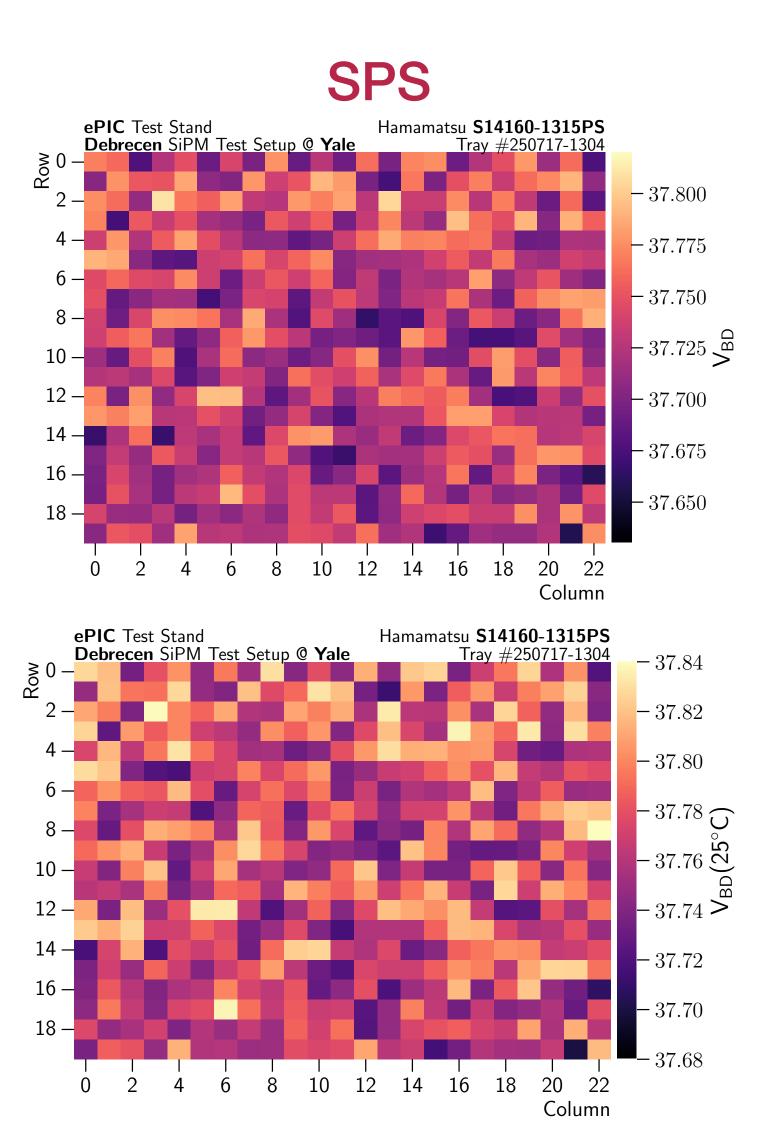


Large difference in outliers from temperature correction!

NOT Temp. Corrected

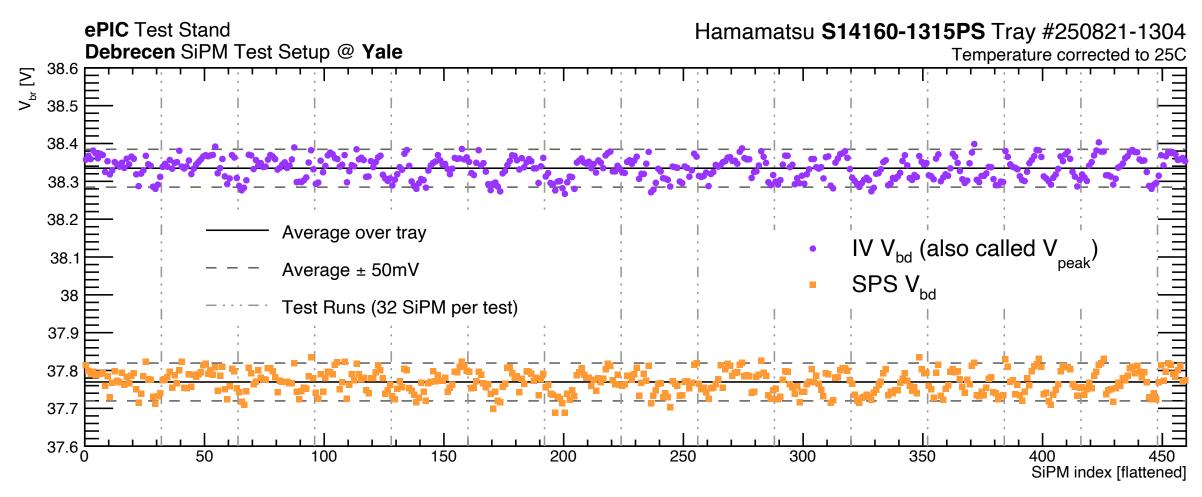
lemp.



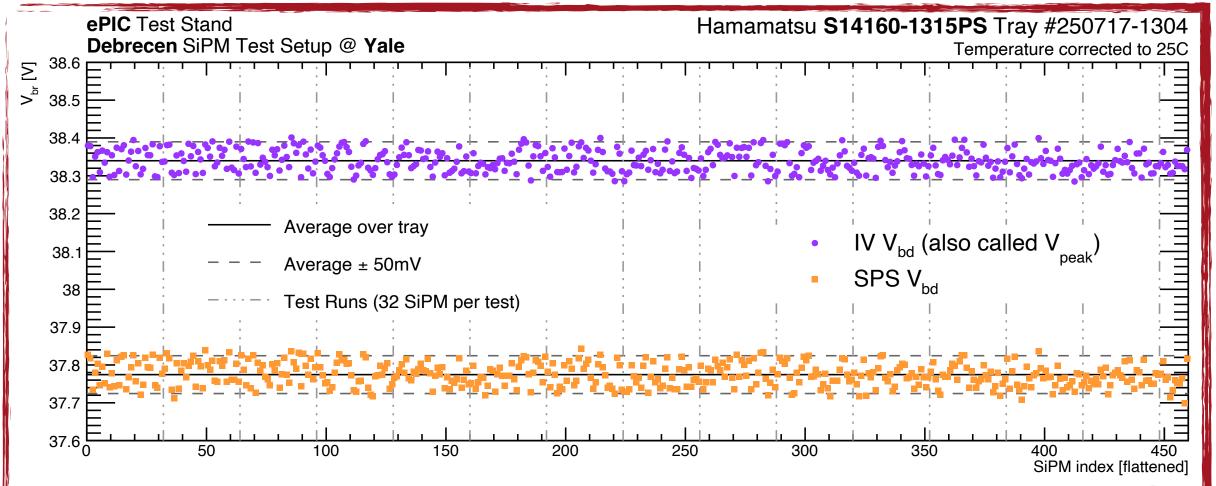


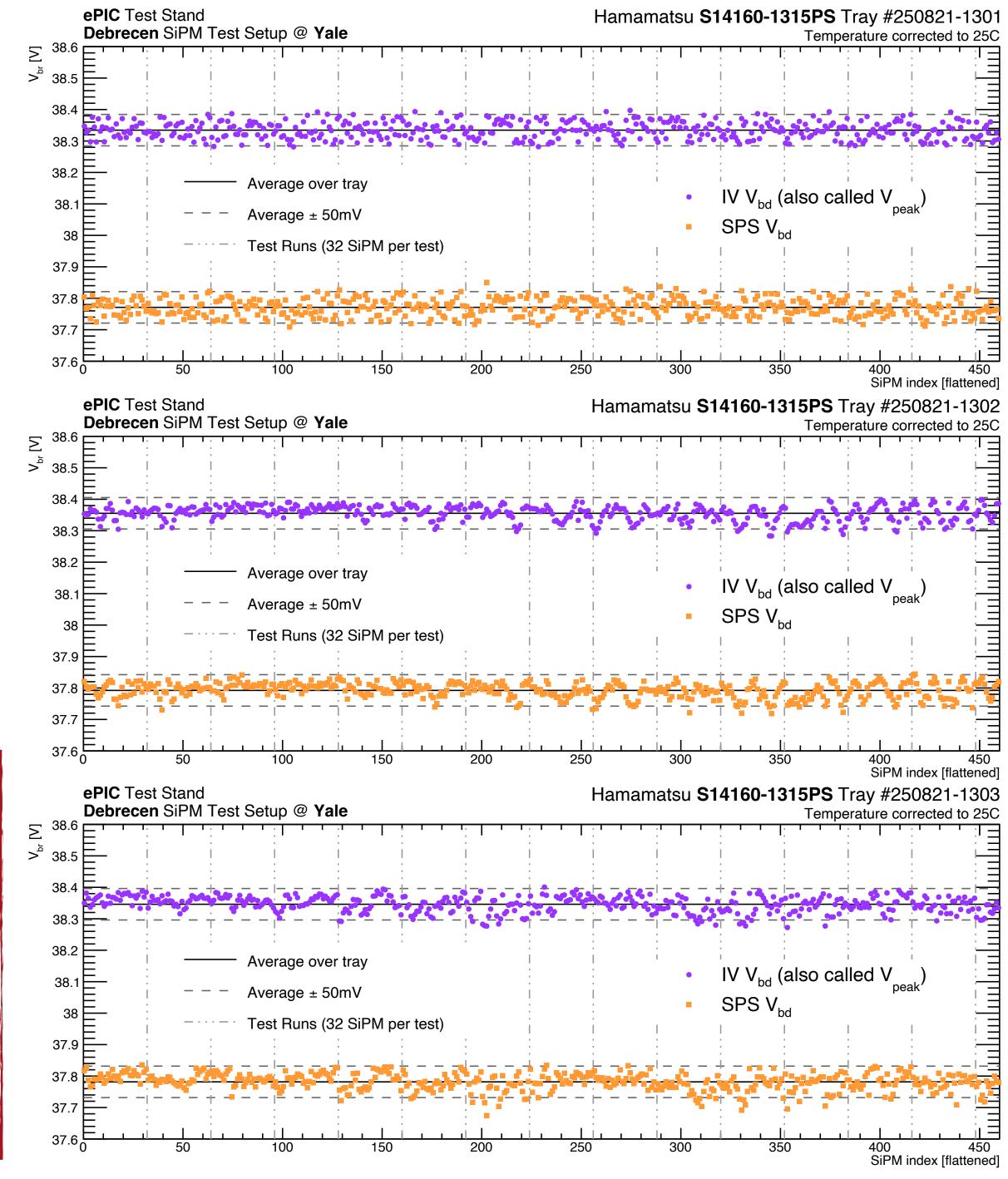
Tray Comparison

SiPMs seem generally comparable in behavior



New Tray 250717-1304





Tray Comparison

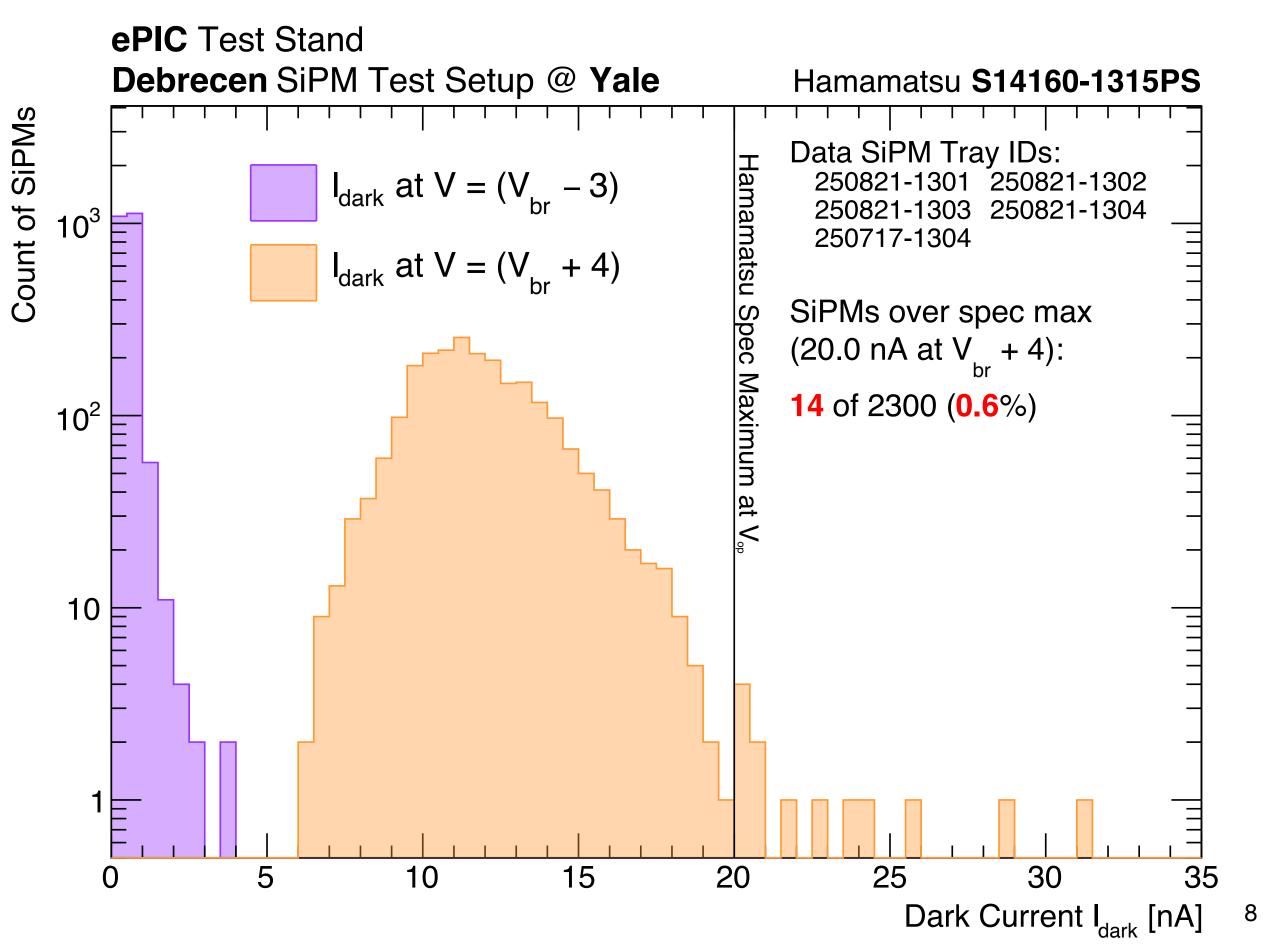
SiPMs seem generally comparable in behavior

New Tray 250717-1304

ePIC Test Stand Debrecen SiPM Test Setup @ Yale Hamamatsu **S14160-1315PS** Count of SiPMs Data SiPM Tray IDs: I_{dark} at $V = (V_{br} - 3)$ 250717-1304 I_{dark} at $V = (V_{br} + 4)$ SiPMs over spec max $(20.0 \text{ nA at V}_{hr} + 4)$: 1 of 460 (0.2%) 10 1 15 20 25 30 10

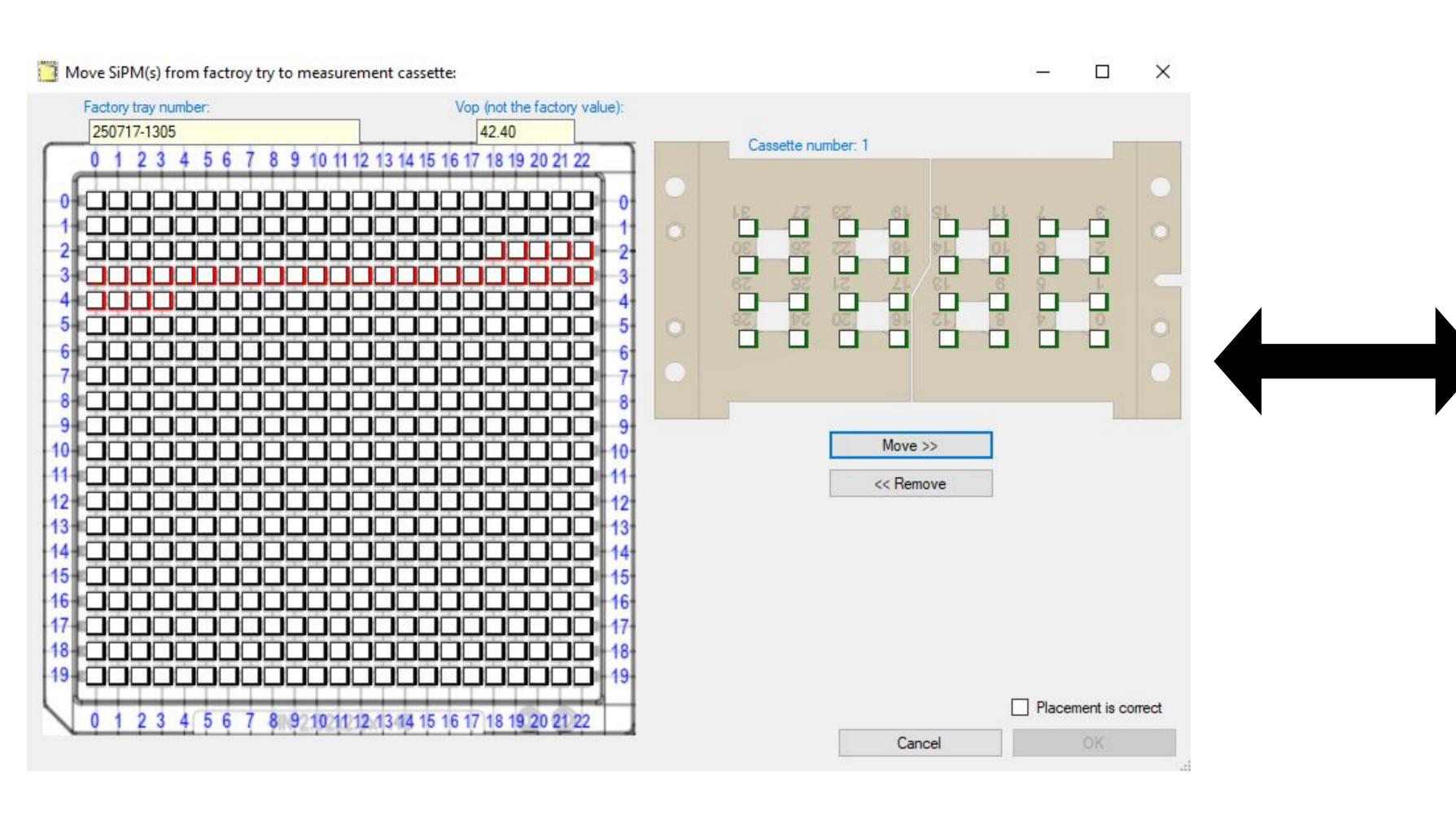
Dark Current I_{dark} [nA]

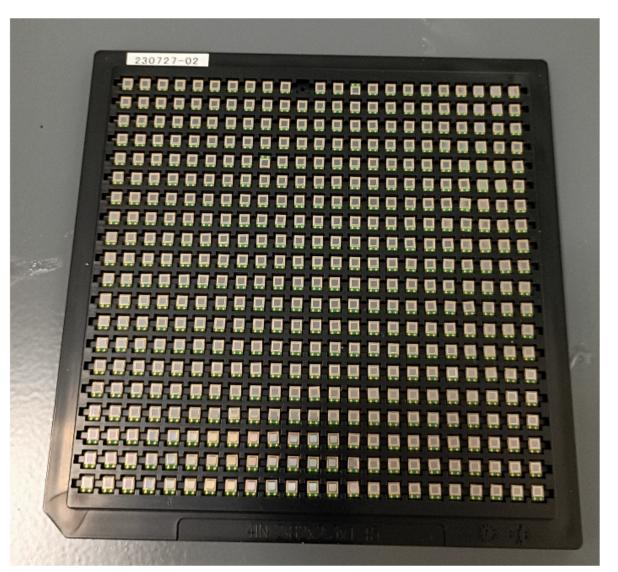
All Tray Data

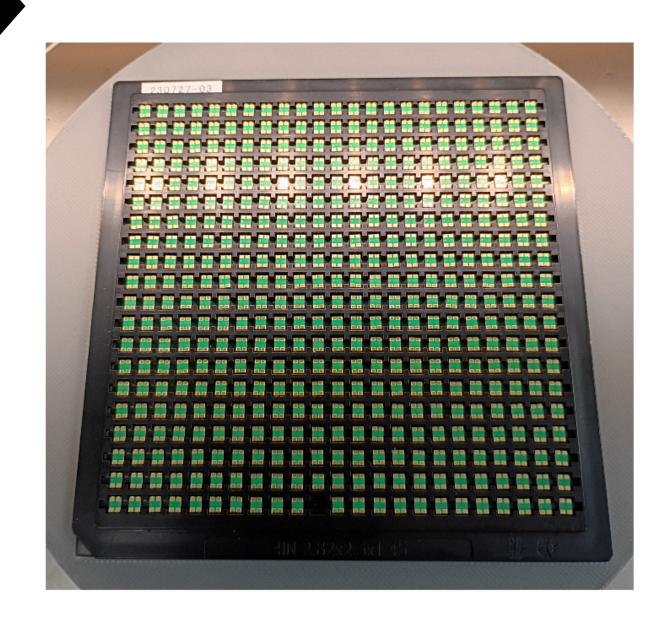


Next Step: Correlating with ORNL

Do we see the same outliers?

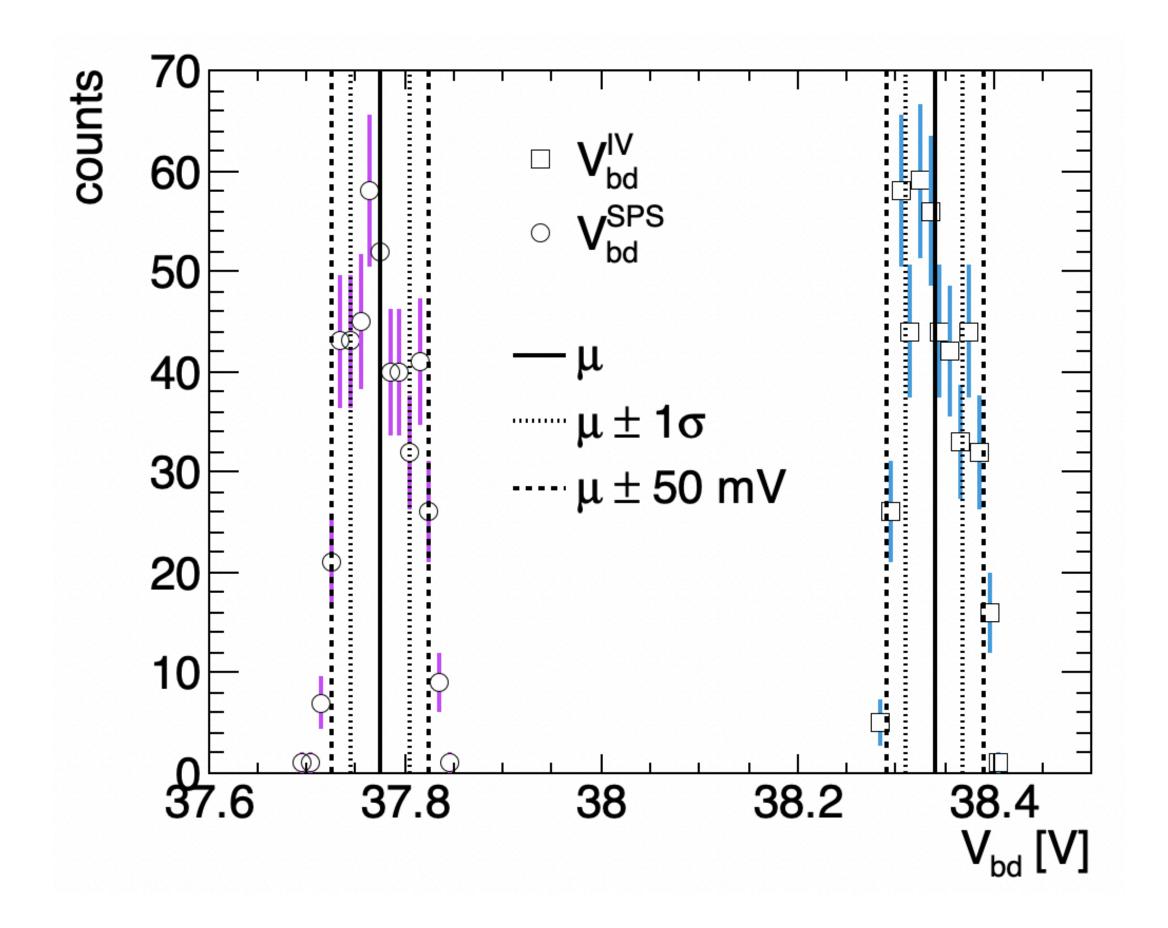






Breakdown voltage distribution

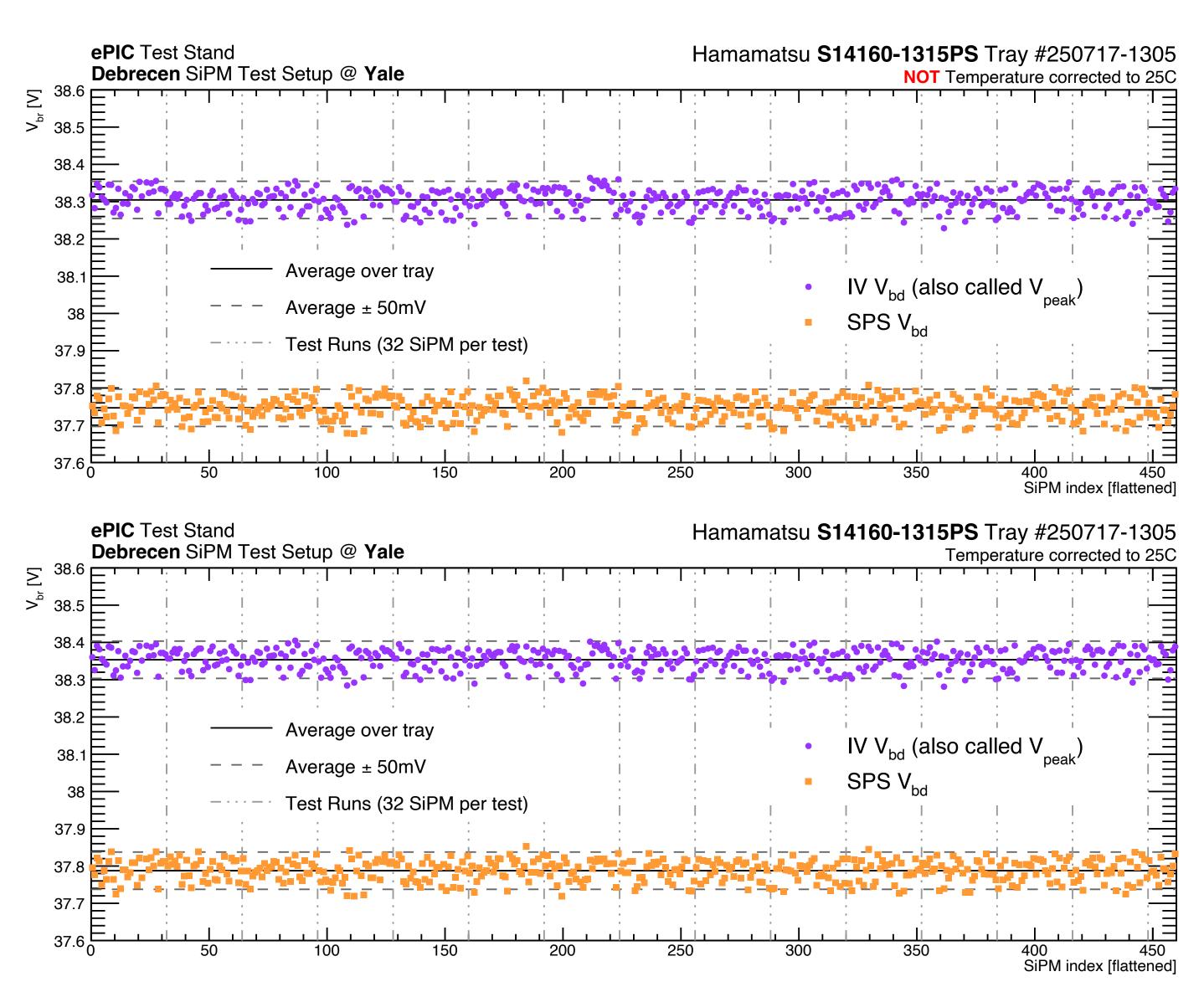
(Temperature-corrected, 250717-1304)



Wednesday 10/29

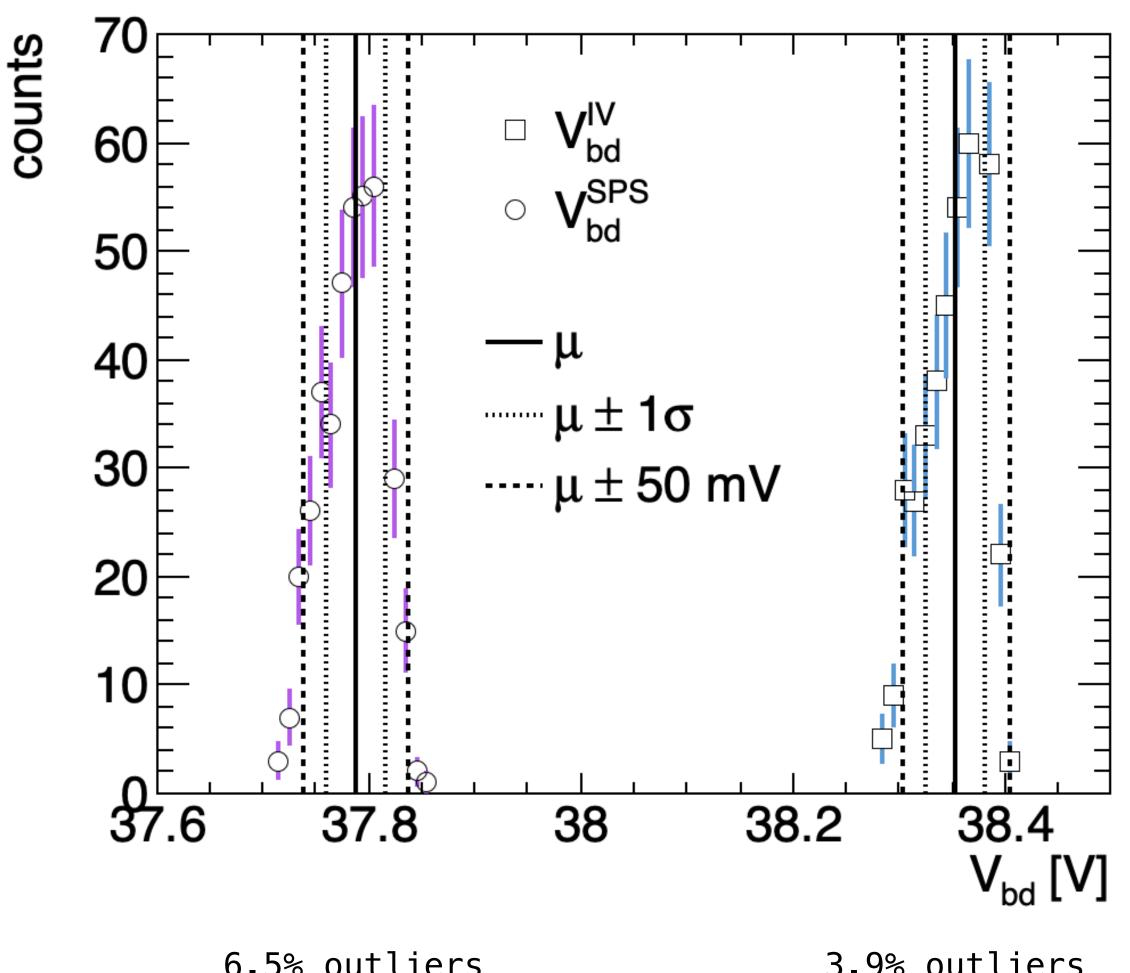
Comparable to 250717-1304:

 Some structured correlations with tray index but largely random



Comparable to 250717-1304:

- Some structured correlations with tray index but largely random
- Fewer outliers in the new tray
- On the same order (~5%) as batch 250821, with most of these close to +/- 50 mV boundary

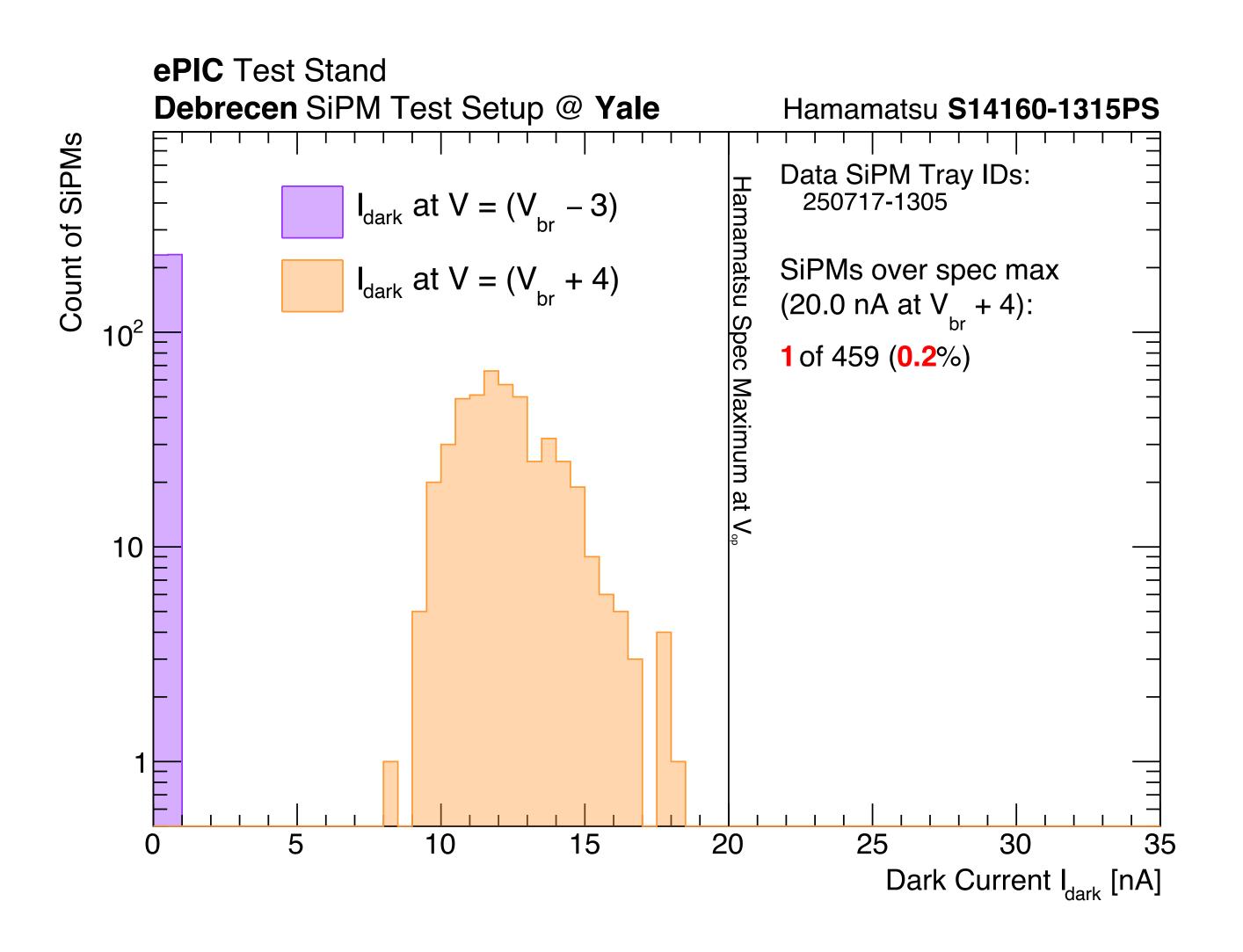


6.5% outliers

3.9% outliers

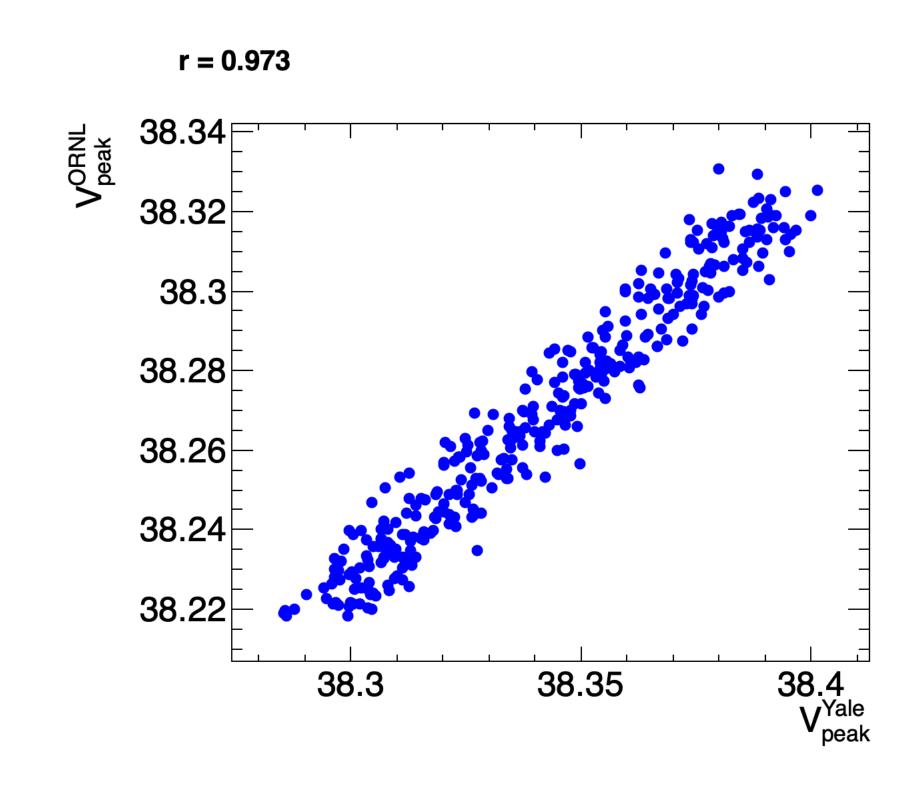
Comparable to 250717-1304:

- Some structured correlations with tray index but largely random
- Fewer outliers in the new tray
- On the same order (~5%) as batch 250821, with most of these close to +/- 50 mV boundary
- Dark current is very well below limits compared to batch 250821



Tray 250717-1304

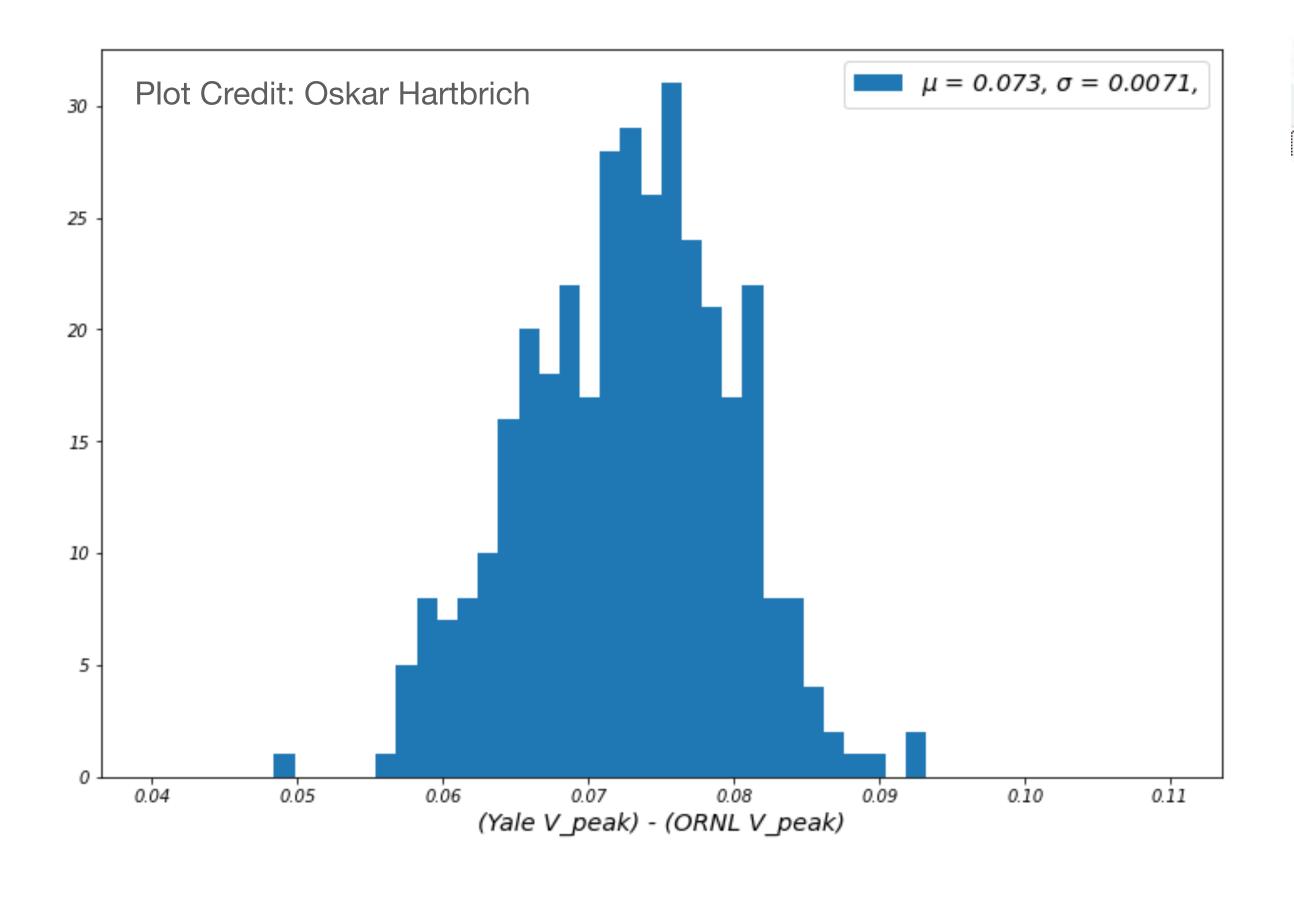
- Observations:
 - Either Yale's T correction seems smaller than expected (~40 mV/C), or another systematic in play (25C at Yale vs 20C at ORNL, but only 70 mV offset on average)
 - Tight SiPM-to-SiPM correlation for this tray (~7 mV spread)

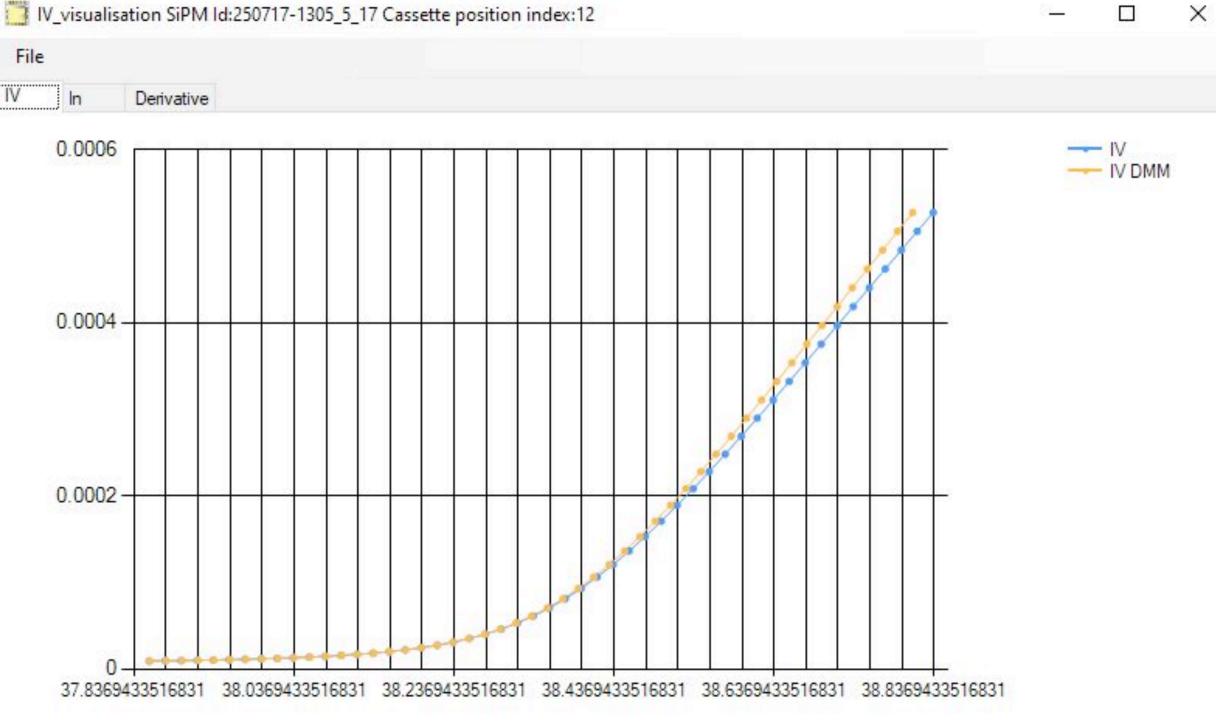


[Note: this plot is only for ~350 SiPMs]

Temperature Correction

IV Measurement to blame for a constant offset?





Debrecen code: 50 step measurement, smoothed with ROOT::Smooth()

Temperature Correction

How is the Temperature Correction performed?

Code is (if I'm looking in the right place) constant offset, but output data seems more dynamic?

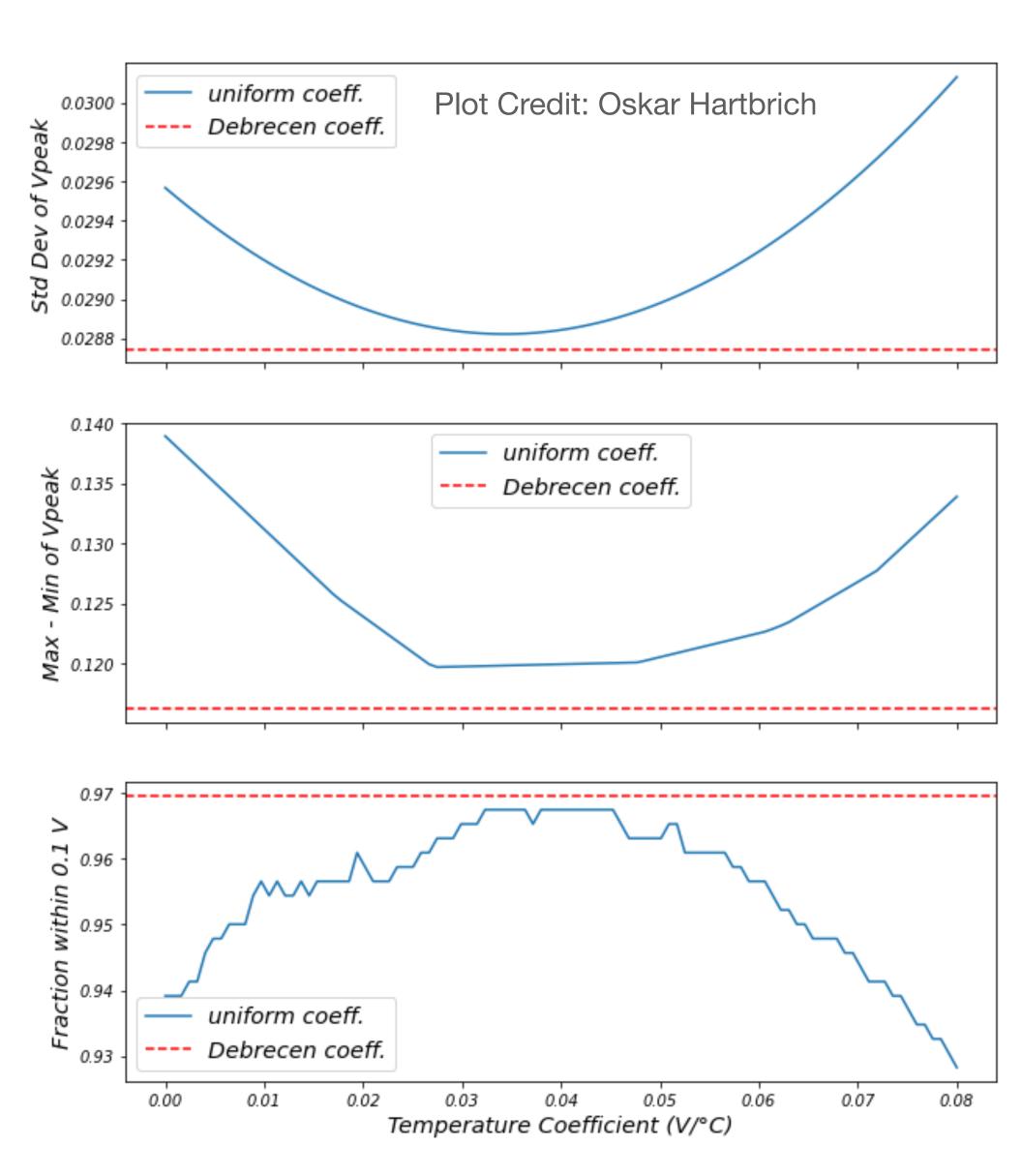
```
const double tempCoeff = 0.034; //temperature compensation coefficient V/Celsius from
SP14160-1315PS datasheet
```

```
double calcBreakdownTo25C_nearest(double BreakdownVoltage)
{
   double temp = GetSIPMTemp();
   const double operatingTemp = 25.0; // Celsius

   return BreakdownVoltage + ((operatingTemp - temp) * tempCoeff);
}

double calcBreakdownTo20C_nearest(double BreakdownVoltage)
{
   double temp = GetSIPMTemp();
   const double operatingTemp = 20.0; // Celsius

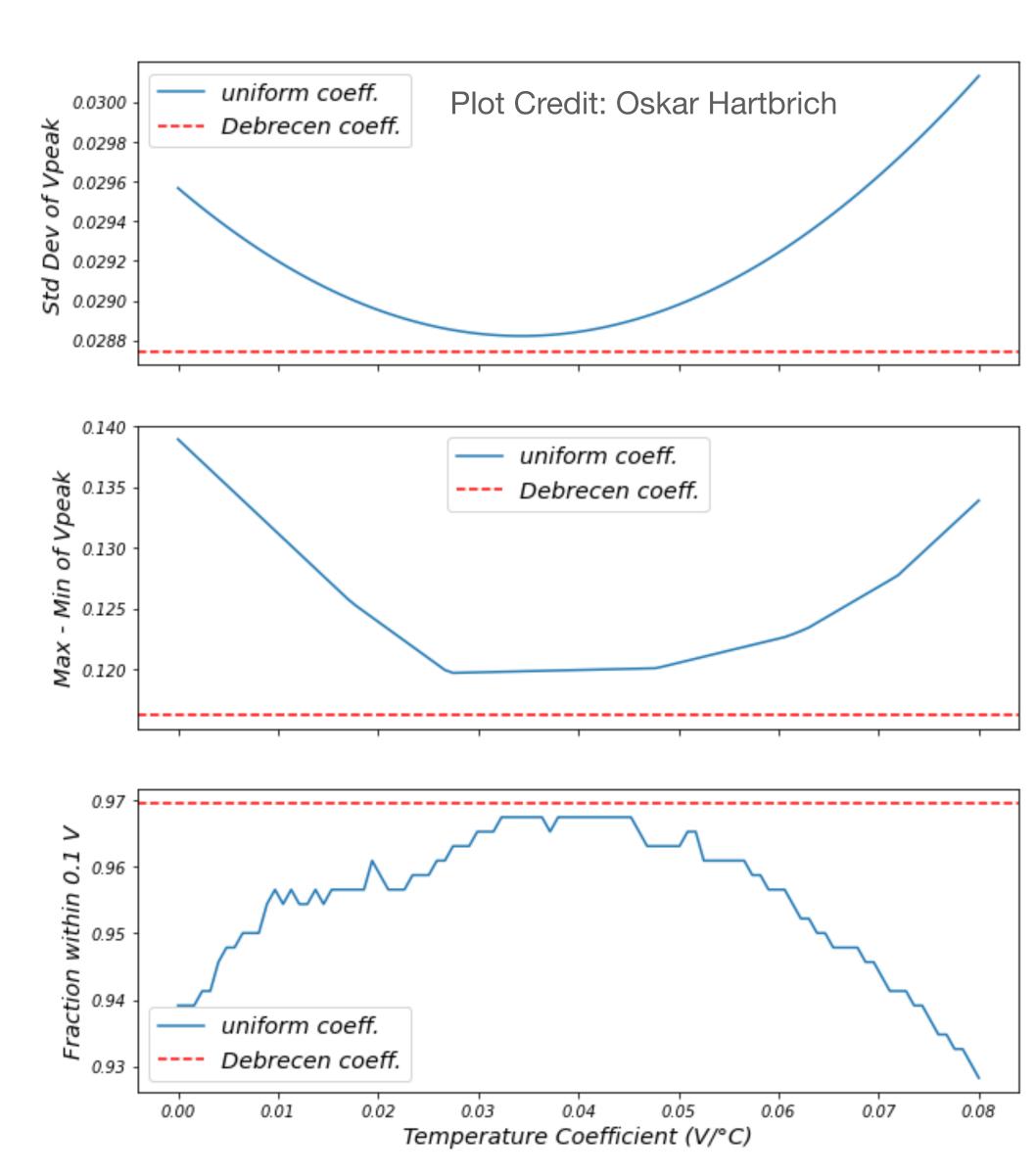
   return BreakdownVoltage + ((operatingTemp - temp) * tempCoeff);
}
```



Temperature Correction

Possibly due to temperature measurement averaging?

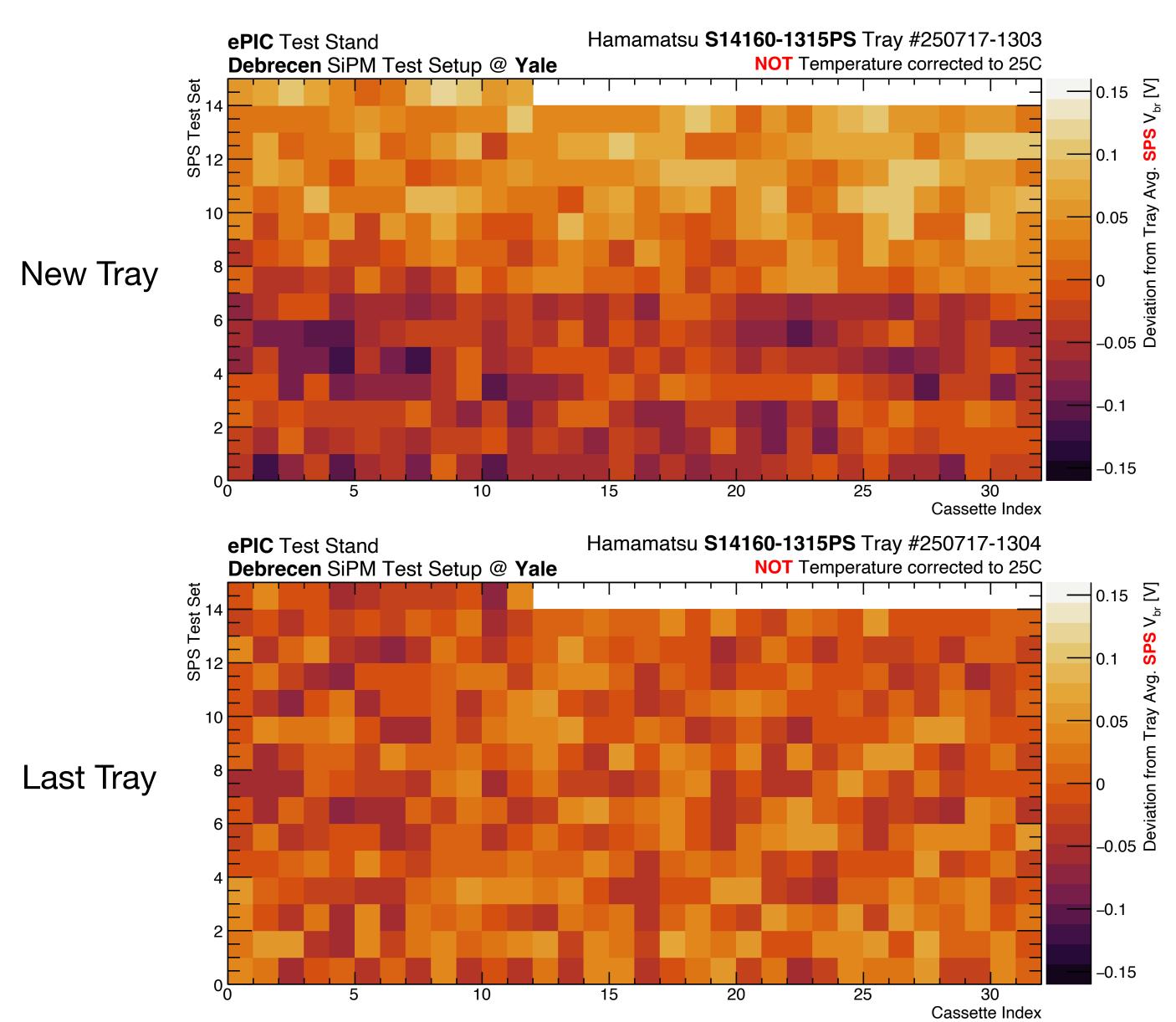
```
const uint8_t temp_sensor_lut[32] =
    {0,0,4,4,0,0,4,4,1,1,5,5,1,1,5,5,2,2,6,6,2,2,6,6,3,3,7,7,3,3,7,7};
double GetSIPMTemp() //gradiens kompenzáció??? uint8_t SIPM_pos, uint8_t socket
  double temp = 0;
  double avg_temp[8];
  for(int i=0;i<8;i++)</pre>
   avg_temp[i] = (InitialTemp[i] + FinalTemp[i])/2;
  temp = avg_temp[temp_sensor_lut[socket]];
   return temp;
```



Monday 11/3

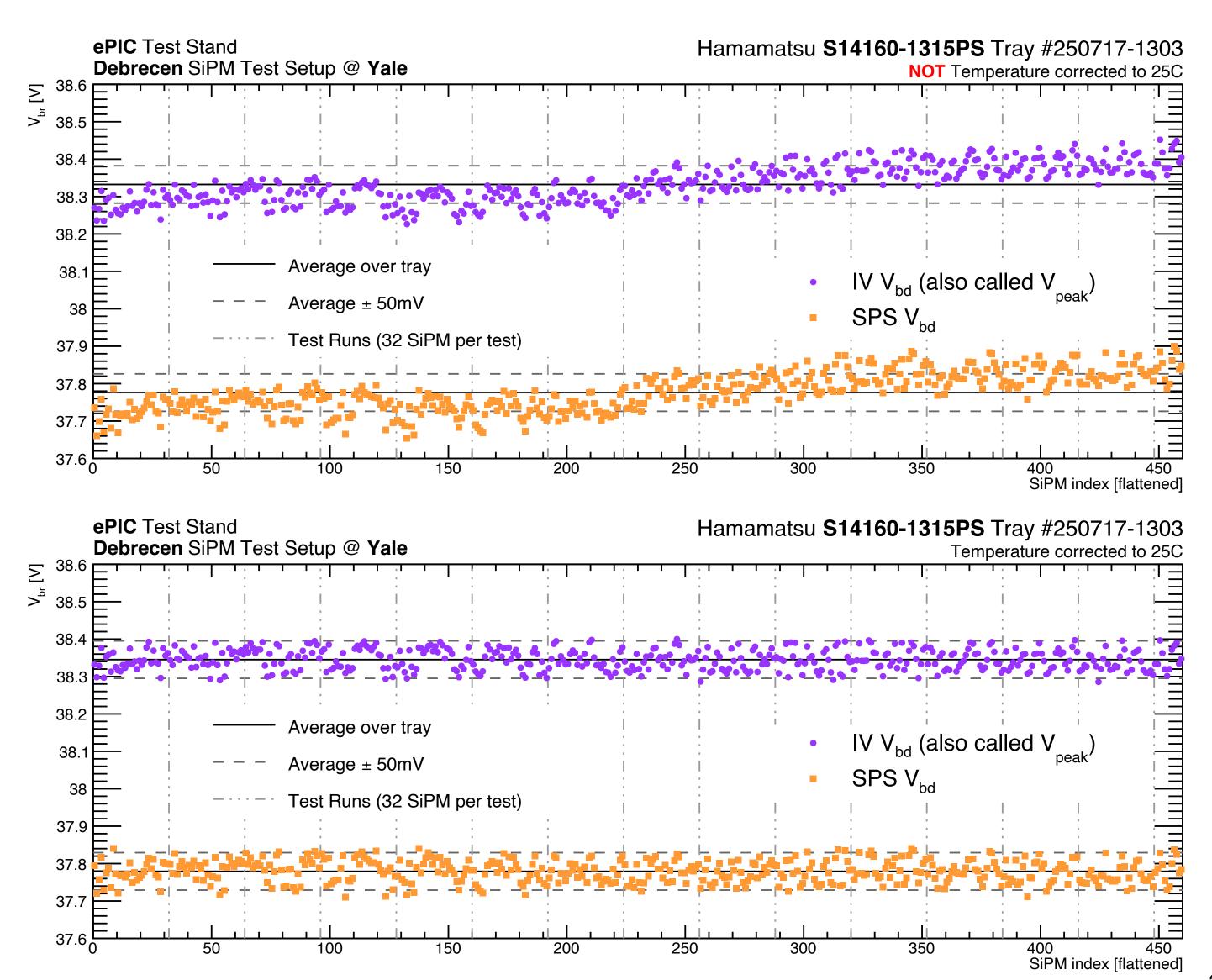
Some interesting results"

 Wild temperature change as Lab heating kicks on



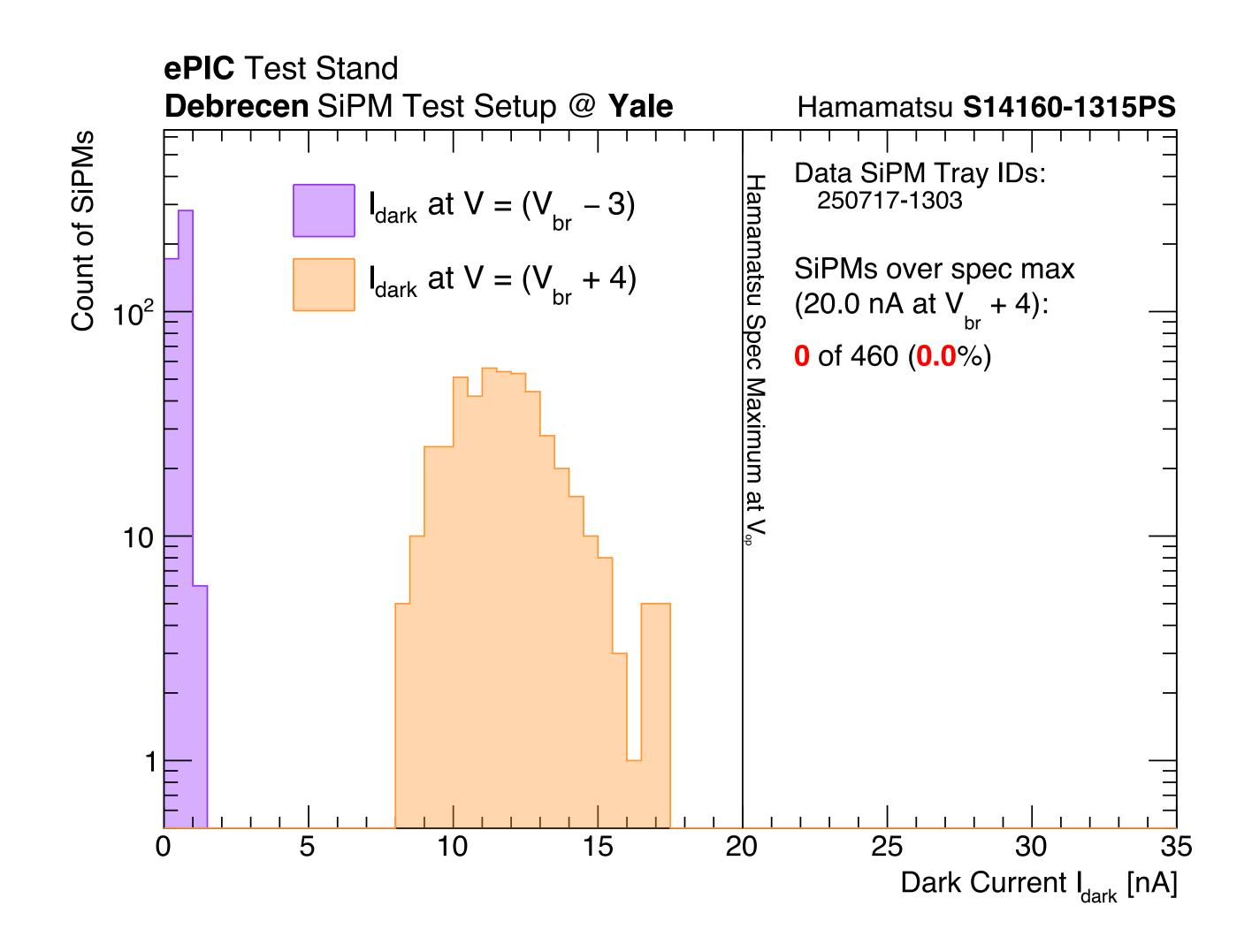
Some interesting results"

- Wild temperature change as Lab heating kicks on
- Temperature correction seems to still work quite well!
- 36 outliers from avg +/-50mV (~7.6%), more than 1305 but less than 1304



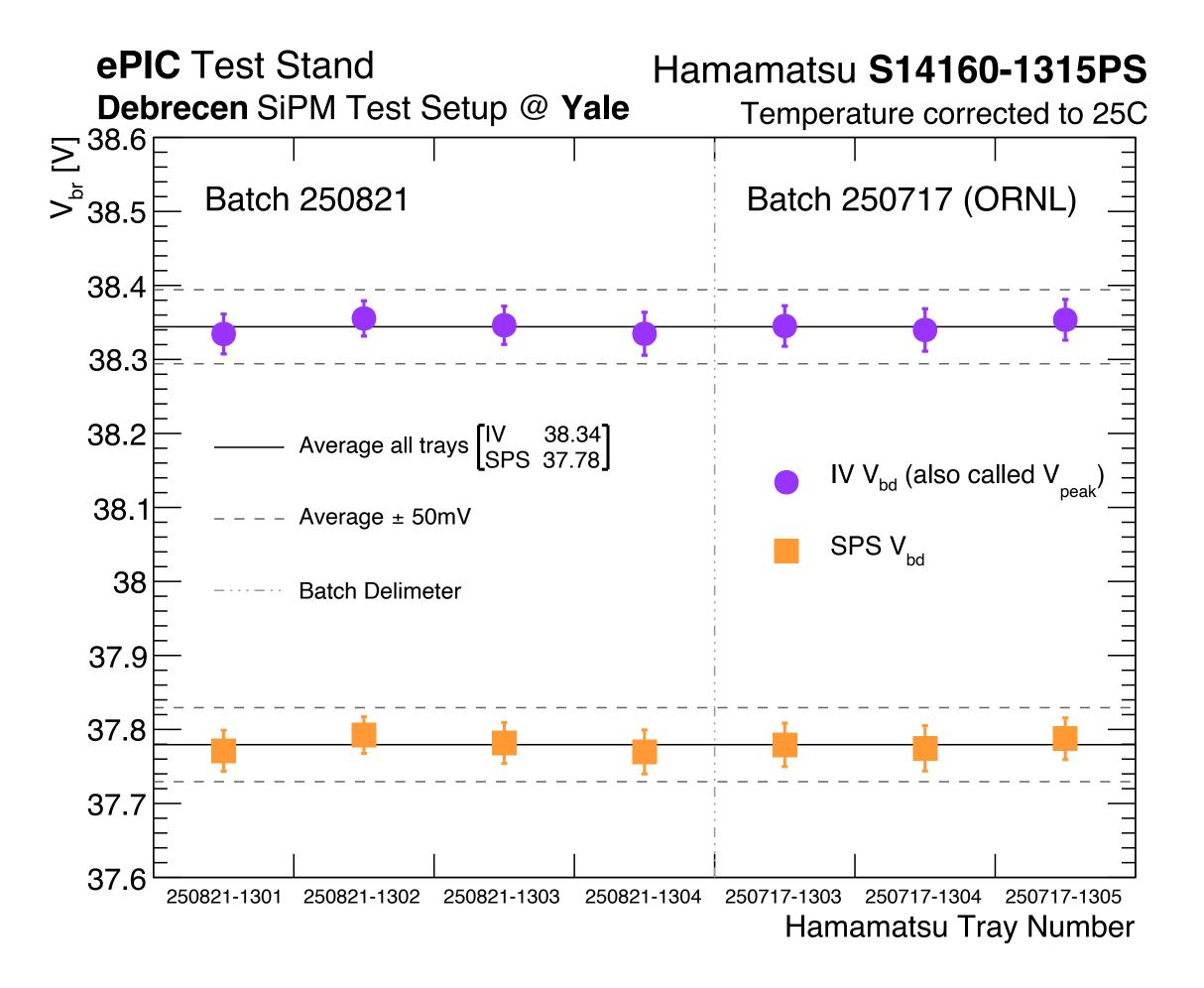
Some interesting results"

- Wild temperature change as Lab heating kicks on
- Temperature correction seems to still work quite well!
- 36 outliers from avg +/-50mV (~7.6%), more than 1305 but less than 1304
- No dark current outliers, in line with other 250717 trays.



All Data So Far

Total $V_{\rm bd}$ outliers: 234 of 3219 (7.3%) (relative to global average, 129 for +/- 55mV)



Total I_{dark} outliers: 15 of 3219 (0.5%)

